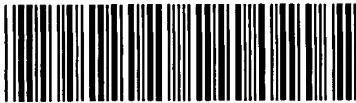


**Search Notes**

Application/Control No.

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Examiner

shih-wen hsieh

Applicant(s)/Patent under  
Reexamination

UWAGAKI ET AL.

Art Unit

2861

**SEARCHED**

Class	Subclass	Date	Examiner
347	33,29,30 32	6/8/2007	SWH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR